

<b>Issue Classification</b>				Application/Control No. 10/827,285				Applicant(s)/Patent under Reexamination CHEN ET AL.			
				Examiner DEVIN HANAN				Art Unit 3745			

ISSUE CLASSIFICATION													
ORIGINAL				INTERNATIONAL CLASSIFICATION									
CLASS		SUBCLASS		CLAIMED				NON-CLAIMED					
416		234		F	04	D	29	/38				/	
CROSS REFERENCES												/	
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)											/	
416	178	186R										/	
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<i>Devin Hanan 2/1/2008</i> Devin Hanan 2/1/2008 (Assistant Examiner) (Date)				<i>Edward K. Look</i> EDWARD K. LOOK SUPERVISORY PATENT EXAMINER (Print Name) TECHNOLOGY CENTER 1600 <i>2/14/08</i>				Total Claims Allowed: 2					
(Legal Instruments Examiner) (Date)								O.G. Print Claim(s) 1				O.G. Print Fig. 5	

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant														
1	Final	Original		Final	Original									
1	1			31			61			91			121	
-	1	2		32			62			92			122	
-	1	3		33			63			93			123	
-	1	4		34			64			94			124	
-	1	5		35			65			95			125	
-	1	6		36			66			96			126	
2	7			37			67			97			127	
-	1	8		38			68			98			128	
-	1	9		39			69			99			129	
-	1	10		40			70			100			130	
-	1	11		41			71			101			131	
-	1	12		42			72			102			132	
-	13			43			73			103			133	
-	14			44			74			104			134	
-	15			45			75			105			135	
-	16			46			76			106			136	
-	17			47			77			107			137	
-	18			48			78			108			138	
-	19			49			79			109			139	
-	20			50			80			110			140	
-	21			51			81			111			141	
-	22			52			82			112			142	
-	23			53			83			113			143	
-	24			54			84			114			144	
-	25			55			85			115			145	
-	26			56			86			116			146	
-	27			57			87			117			147	
-	28			58			88			118			148	
-	29			59			89			119			149	
-	30			60			90			120			150	